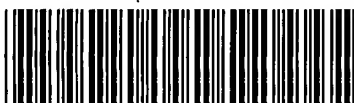


Search Notes

Application/Control No.

10/520,031

Examiner

Young J. Kim

Applicant(s)/Patent under
Reexamination

MARTON ET AL.

Art Unit

1637

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) see enclosed for text-search strategy	11/21/2007	YJK
Inventor name search	11/21/2007	YJK